

IN THE CLAIMS

Please amend the claims as follows:

- 1-4. (Canceled)
5. (Currently Amended) A method of testing a driver comprising:
driving a known reference channel with the driver, wherein the known reference channel
is specified as a worst-case channel that displays a maximum allowable loss versus frequency
characteristic;
measuring at least one parameter at an output of the known reference channel; and
comparing a measurement against a requirement to determine if the driver passes a test.
6. (Original) The method of claim 5 wherein the method is performed by computer
simulation.
7. (Currently Amended) The method of claim 6 wherein the known reference channel is
specified by s-parameters.
8. (Canceled)
9. (Currently Amended) The method of claim 5 wherein the known reference channel is
further specified by a minimum delay.
10. (Currently Amended) The method of claim 5 wherein the known reference channel is
further specified by a maximum delay.
11. (Original) The method of claim 5 wherein the at least one parameter includes an eye
voltage.

12. (Original) The method of claim 5 wherein the at least one parameter includes an eye time.

13. (Canceled)

14. (Currently Amended) A method comprising:

coupling a device under test to a known reference channel, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

measuring at least one parameter at an output of the known reference channel; and

comparing a measurement against a requirement to determine if the device under test passes a test.

15. (Original) The method of claim 14 wherein the device under test comprises a receiver.

16. (Original) The method of claim 14 wherein the device under test comprises a driver.

17. (Original) The method of claim 14 wherein the at least one parameter comprises an eye voltage.

18. (Original) The method of claim 14 wherein the at least one parameter comprises an eye time.

19. (Original) The method of claim 14 wherein the method is performed by computer simulation.

20. (Currently Amended) The method of claim 19 wherein the known reference channel is defined by a set of reference channel parameters.

21. (Original) The method of claim 20 wherein the set of reference channel parameters comprises s-parameters.

22. (Canceled)

23. (Previously Presented) The method of claim 20 wherein the set of reference channel parameters comprises a delay value.

24. (Currently Amended) An apparatus including a medium adapted to hold machine-accessible instructions that when accessed result in a machine performing:

coupling a device under test to a known reference channel, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

measuring at least one parameter at an output of the known reference channel; and

comparing a measurement against a requirement to determine if the device under test passes a test.

25. (Original) The apparatus of claim 24 wherein the device under test comprises a receiver.

26. (Original) The apparatus of claim 24 wherein the device under test comprises a driver.

27. (Original) The apparatus of claim 24 wherein the at least one parameter comprises an eye time.

28. (Currently Amended) An electronic system comprising:

a processor capable of simulating a circuit; and

an SRAM storage medium accessible by the processor, the storage medium to hold instructions that when accessed result in the processor performing:

coupling a device under test to a known reference channel, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

measuring at least one parameter at an output of the known reference channel; and
comparing a measurement against a requirement to determine if the device under passes a test.

29. (Original) The electronic system of claim 28 wherein the device under test comprises a receiver.

30. (Original) The electronic system of claim 28 wherein the device under test comprises a driver.